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Richardson RFPD, Inc.
1950 S. Batavia Ave, Suite 100
Geneva, Illinois 60134

26th May 2021

Subject: Additional testing and packaging site.

PCN-1440

Dear Valued Customer,

MACOM Technology Solutions has a goal of providing redundant manufacturing capability for increased surge capacity as well as an uninterrupted supply chain. In alignment with this goal, we are pleased to announce an additional testing and packaging site for the parts listed in the next pages.

In addition to our current testing and packaging sites, we planned to test and package these parts at our long-standing Contract Manufacturer, Year 2000, Ho Chi Minh City, Vietnam. Year 2000 is a valued, high-quality manufacturing partner for many MACOM products.

In accordance with MACOM Technology Solutions' customer notification policy, you are receiving this notice because you have purchased one or more of the products listed in the previous two-year period.

Please contact your local sales representative if you have any specific questions.

Sincerely

Timothy Daly
Senior Product Line Manager
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Appendix I

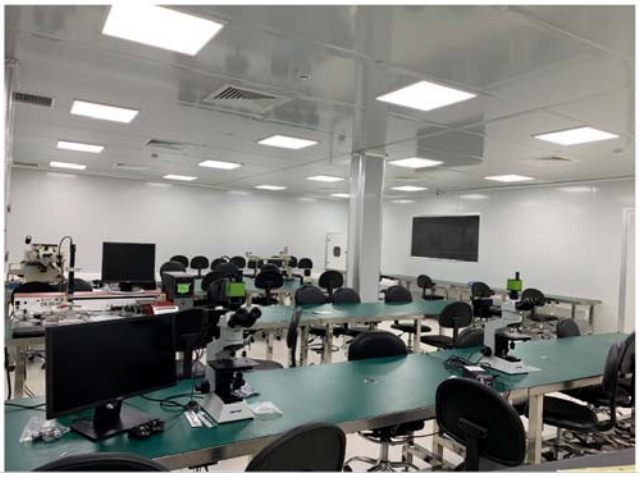
Affected part numbers

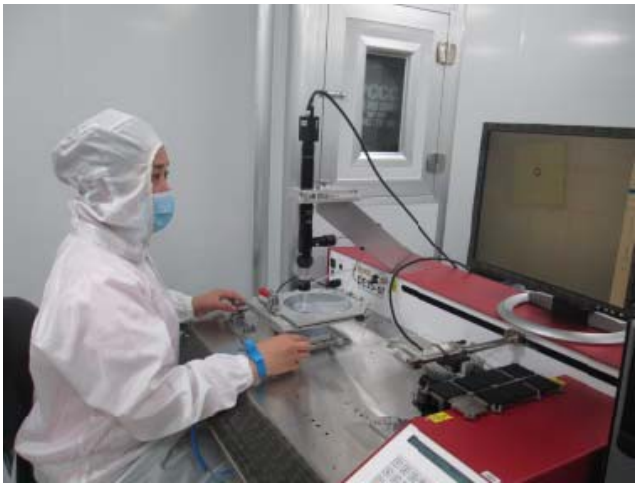
Part Number	Part type
M3X3019	Capacitor
M3X3017	Capacitor
M3X2661	Capacitor
MCC50-50D	Capacitor
M5X5272	Capacitor
MC2S022025-025	Capacitor
910R6J	Capacitor
M3X1833	Capacitor
919R9K	Capacitor
MC2S005010-010	Capacitor
MX51992-11	Capacitor
M3X6183	Capacitor

All the parts to be transferred on this pcn are capacitors. Three representative part numbers(M3X3017, M3X6183 and MCC50D) are tested and qualified in Year 2000(testing data and Cpk see Appendix II), and the rest capacitors can be qualified by similarity to the representative parts.

Appendix II

The new testing and assembly facility



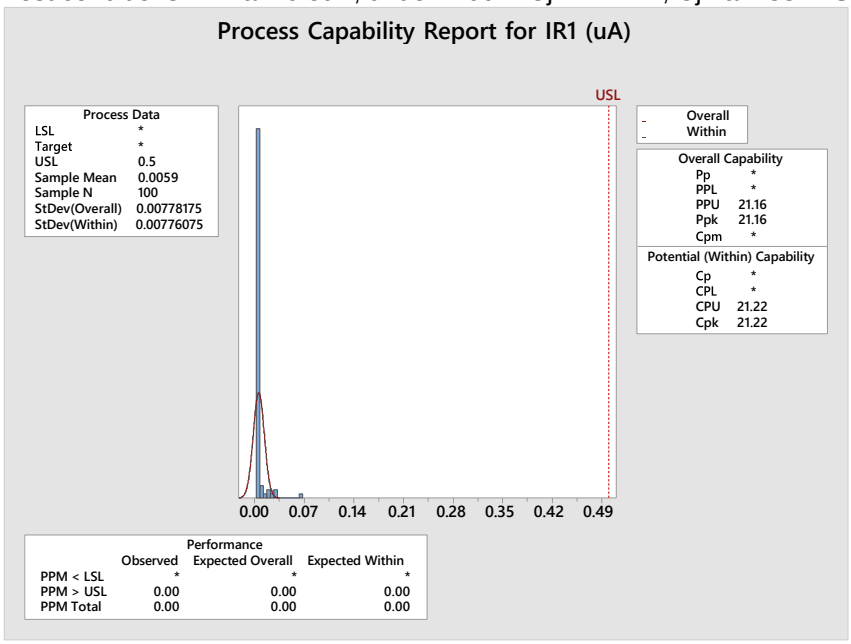


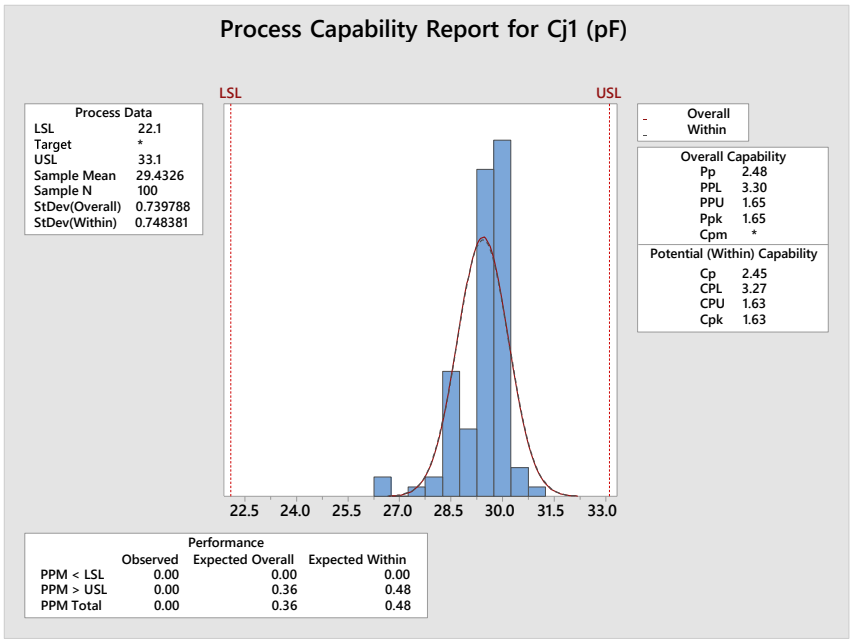
Appendix III

Qualification testing data

1. M3X3017

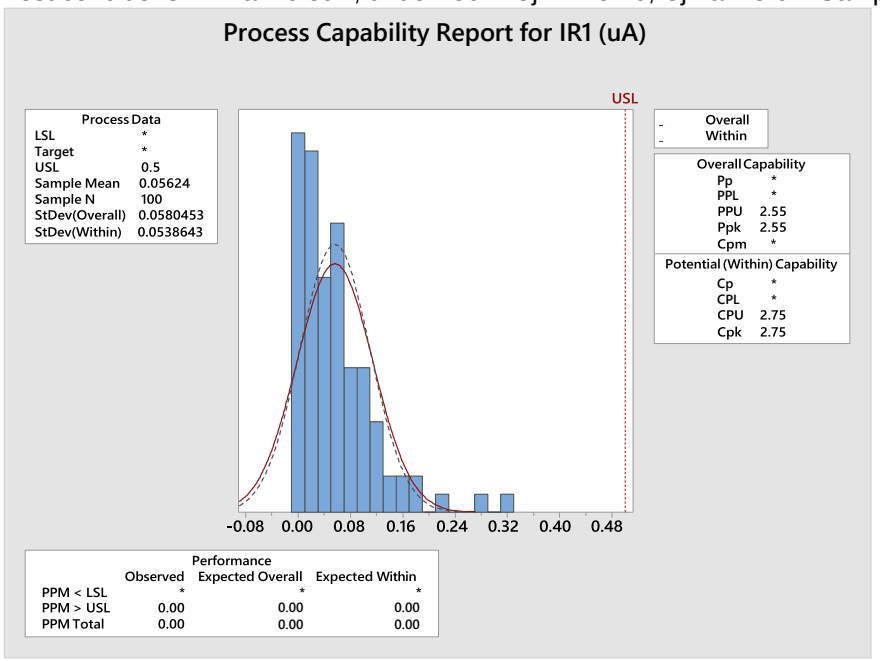
Test conditions: IRmax=0.5uA, under -100V. Cjmin=22.1, Cjmax=33.1. Sample size=100,10 sub-groups.

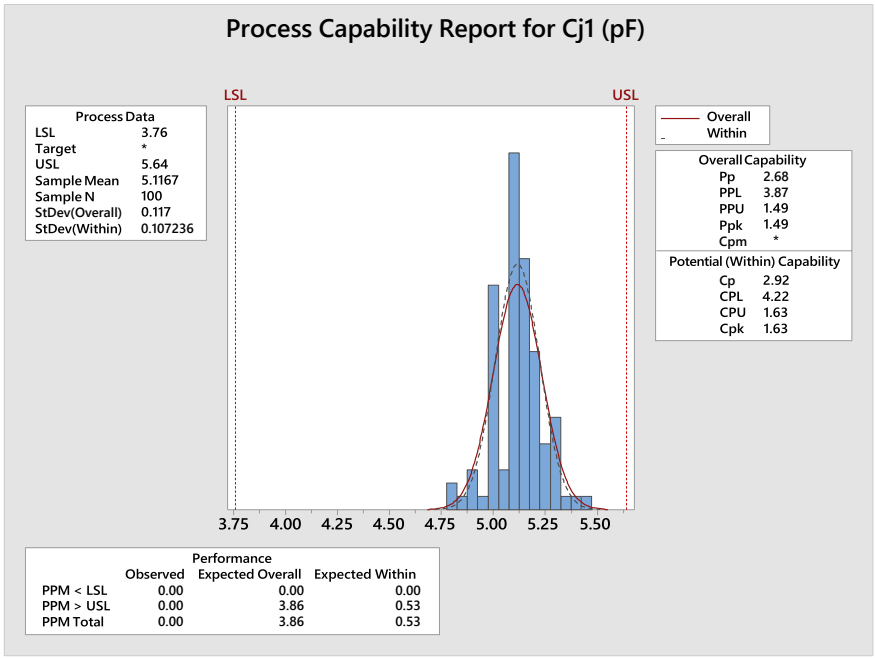




2. M3X6183

Test conditions: IRmax=0.5uA, under -50V. Cjmin=3.76, Cjmax=5.64. Sample size=100,10 sub-groups.





3. MCC50D

Test conditions: IRmax=0.5uA, under -50V. Cjmin=40, Cjmax=60. Sample size=80,10 sub-groups.